

Designation: F 1662 - 95 (Reapproved 2002)

Standard Test Method for Verifying the Specified Dielectric Withstand Voltage of a Membrane Switch¹

This standard is issued under the fixed designation F 1662; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This test method covers the verification of a specified dielectric withstand voltage of a membrane switch.

2. Terminology

- 2.1 Definitions:
- 2.1.1 *dielectric withstand voltage*—the maximum voltage a dielectric can withstand without a visual change from a voltage discharge or specified change of insulation resistance, or both.
- 2.1.2 *insulation resistance, R*—the electrical resistance between test points.
- 2.1.3 *membrane switch*—a momentary switching device in which at least one contact is on, or made of, a flexible substrate.
- 2.1.4 *test points*—two preselected mutually insulated locations on switch assembly.

3. Significance and Use

- 3.1 Dielectric withstand voltage testing is useful for design verification, quality control of materials, and workmanship.
- 3.2 This test is designed to determine product integrity and resistance at voltage levels that exceed normal operating levels.
 - 3.3 Specific areas of testing are, but not limited to:
 - 3.3.1 Conductor/dielectric/conductor crossing point,
 - 3.3.2 Close proximity of conductors, and
- 3.3.3 Any other conductive surface such as shielding or metal backing panel.
- 3.4 Dielectric withstand voltage testing may be destructive and units that have been tested should be considered unreliable for future use.

4. Interferences

- 4.1 The following parameters may affect the results of this test:
 - 4.1.1 Humidity,
 - 4.1.2 Contamination,
 - 4.1.3 Barometric pressure, and
 - 4.1.4 Temperature.

Current edition approved Nov. 10, 1995. Published January 1996.

5. Apparatus

5.1 *Electric Device*, suitable to provide a controlled dc or ac voltage.

6. Procedure

- 6.1 Pretest Setup:
- 6.1.1 Measure the insulation resistance between the two test points. Record insulation resistance as R_i .
- 6.1.2 Connect two test points on the switch assembly to the voltage source.
 - 6.2 In-Process Test—Constant Voltage Method:
 - 6.2.1 Adjust voltage and frequency to a specified level.
- 6.2.2 Apply voltage to switch assembly for a specified interval.
 - 6.3 In Process Test—Ramp Voltage Method:
- 6.3.1 Set the following parameters to specified levels (if applicable):
 - 6.3.1.1 Voltage ramp rate, and
 - 6.3.1.2 Maximum ramp voltage.
 - 6.3.2 Perform test.
 - 6.4 Disconnect switch assembly from power supply.
 - 6.5 Inspect switch assembly for visual change.
- 6.6 Measure the insulation resistance using the same procedure used in 6.1.1.
 - 6.7 Record insulation resistance as $R_{\rm f}$.

7. Calculation

7.1 Calculate the change in the insulation resistance as follows:

 ΔR = Change in Insulation Resistance = $|R_i - R_f|$

8. Report

- 8.1 Report the following information:
- 8.1.1 Temperature,
- 8.1.2 Relative humidity,
- 8.1.3 Barometric pressure,
- 8.1.4 Specified voltage,
- 8.1.5 Actual applied voltage or failure voltage,
- 8.1.6 Frequency of applied voltage,
- 8.1.7 Duration of applied voltage (if applicable),
- 8.1.8 Description of test equipment,
- 8.1.9 Initial voltage and voltage ramp rate (if applicable),

¹ This test method is under the jurisdiction of ASTM Committee F01 on Electronics and is the direct responsibility of Subcommittee F01.18 on Membrane Switches